

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	98	(DFT of (design adj (for adj testability))) same (analysis same synthesis)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/17 11:53
L2	13	(DFT of (design adj (for adj testability))) same (analysis same synthesis) and (logic adj block\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/17 11:55
L3	1	(DFT of (design adj (for adj testability))) same ((divid\$4 or partition\$4) same (analysis same synthesis) and (logic adj block\$2))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/17 11:56
L4	4	(DFT of (design adj (for adj testability))) same (analysis same synthesis) and ((divid\$4 or partition\$4) same (logic adj block\$2))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/17 12:06
L5	1	(DFT of (design adj (for adj testability))) and ((divid\$4 or partition\$4) same (logic adj block\$2)) and (setup adj sequence)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/17 12:07
L6	1	((scan adj cell) adj replacement) and (encod\$4) and (cost adj function)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/17 12:11
L7	1	((scan adj cell) adj replacement) and (affinity or similarity) and (characteristic\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/17 12:13
S1	2399	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:01
S2	1855	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 10:39
S3	1468	716/6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 10:39

S4	0	(716/4).ccls. and (affinity adj (scan adj replacement))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:02
S5	0	(716/5).ccls. and (affinity adj (scan adj replacement))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:02
S6	0	(716/6).ccls. and (affinity adj (scan adj replacement))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:03
S7	0	("716"/\$).ccls. and (affinity adj (scan adj replacement))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:03
S8	0	("716"/\$).ccls. and (affinity same (scan adj replacement))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:03
S9	1	(affinity same (scan adj replacement))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:03
S10	571	702/181	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:39
S11	4	(702/181).ccls. and (DFT or (design adj (for adj testability)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:44
S12	130	("716"/\$).ccls. and (DFT or (design adj (for adj testability)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:44
S13	0	("716"/\$).ccls. and (DFT or (design adj (for adj testability))) and ((multi\$4 adj cycle) same (setup adj sequence))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:46

S14	0	("716"/\$.ccls. and (DFT or (design adj (for adj testability))) and ((multi\$4 adj cycle) and (setup adj sequence))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:47
S15	1	(DFT or (design adj (for adj testability))) and ((multi\$4 adj cycle) and (setup adj sequence))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/12 11:47

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